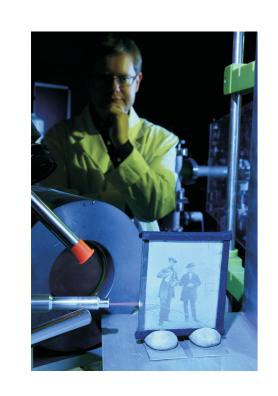
Recent upgrades of the external beamline at MIC



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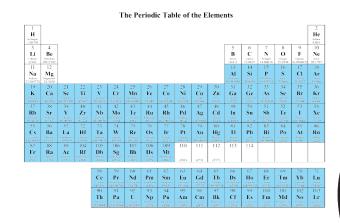
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2 MeV Tandetror Microbeam

Schematics of Tandetron, 2MV ion accelerator at MIC



elements detectable by PIXE method

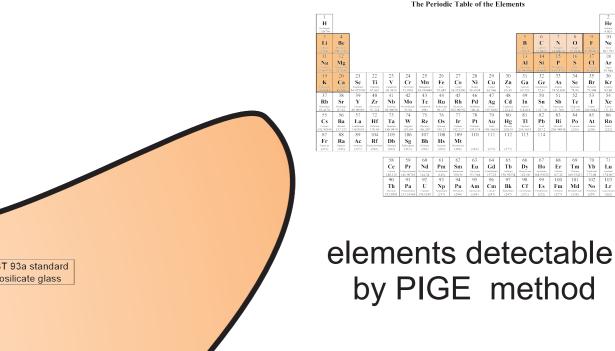
PIGE

Proton Induced Gamma-ray Emission

Detection of light elements through production of gamma rays in a proton induced nuclear reaction.

lon

beam



RBS

Rutherford Back Scattering

Simple system for RBS measurements

in He atmosphere was made at MIC.

Resulting spectra are of comparable

PIXE

Proton Induced X-ray Emission

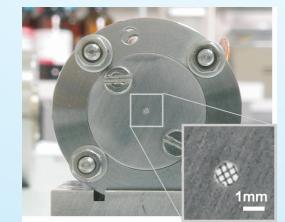
PIXE is an ion-beam based analysis method capable of measuring concentration of multiple elements heavier than Al simultaneously. Detection limit for most elements is around 10ppm and detection depth is around 100um.

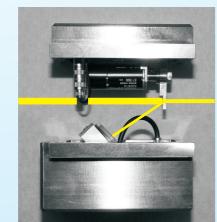
$$Y_{i} = \frac{\Delta\Omega}{4\pi} N_{p} N_{A} \frac{\varepsilon_{i} \eta_{i} \sigma_{i}^{x}}{M_{i}} \frac{q_{i}}{\cos \alpha}$$

Normalization (measuring N_D)

Basic parameter for obtaining quantitative results is a number of ions (protons) which hit the target (Np). There were two possibilities for measuring the proton dose added recently at the external beamline at MIC, wire mesh and chopper.

Platinum wire mesh (Pt90Rh10) intersects the ion beam and collects charge which is proportional to the charge (number of protons) deposited on the target¹.





Au peak

Chopper is a gold plated piece of carbon, which intersects a proton beam periodically. Some protons are recoiled into the RBS detector. Surface of Au peak is proportional to the proton dose on the target.

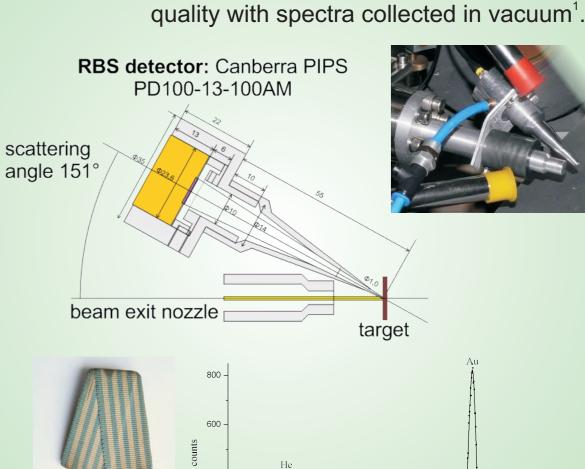
analysis

("IBA") is an important **family of modern** analytical techniques involving the use of MeV ion beams to probe the composition and obtain elemental depth profiles in the near-surface layer of solids. All IBA methods are

highly sensitive and allow the detection of elements in the

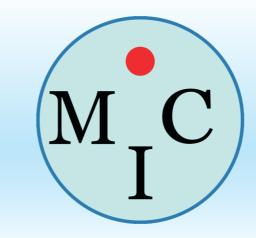
sub-monolayer range. Atomic depth resolution can be achieved, but requires special equipment. The analyzed depth ranges from a few ten nanometers to a few ten micrometers. IBA methods are

always quantitative with an accuracy of a few percent. Channeling allows to determine the depth profile of damage in single crystals. (source: Wikipedia)

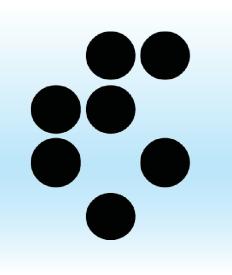


RBS spectrum of gilded medal of bravery from II world war. Thickness of gold layer is 0.4 µm.





VI croanalytical Centre http://www.rcp.ijs.si/mic Ion Accelerator: HV 2MV Tandetron Department for Low and Medium Energy Physics at Reactor Centre Podgorica Jožef Stefan institute.





External beamline

- in-air proton beam,
- measurements of samples not suitable for vacuum
- (e.g. liquids, big, delicate objects)
- use for analysis of samples for:
 - Archaeology (metal and glass artefacts, pottery, wood...)

Depth resolution

With an RBS method we can

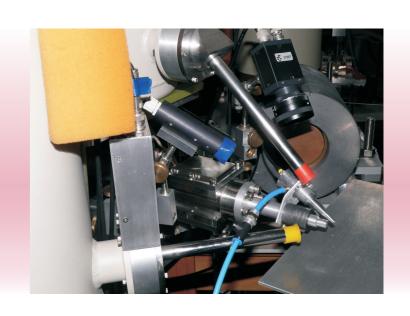
easily detect layers of heavier

elements on the substrate of

lighter elements and determine

its thickness.

- Art (paintings, glass work, ...)
- Forensics (measurement of fibres²)



REFERENCES:

[1] D. Jezeršek et al. External beamline setup for plated target investigation, Nucl. Instr. and Meth. B (2010), doi: 10.1016/j.nimb.2010.02.118

[2] D. Jezeršek et al. Analysis of textile fibers by in-air PIXE, Surface and Interface Analysis (2010), Vol 42, Issue 5, pp. 358-362.